

LMP4435SSF 30V P-Channel MOSFET

Features

- -30V/-9A, $R_{DS(ON)} < 18m\Omega @ V_{GS} = -10V$
- -30V/-7A, $R_{DS(ON)} < 26m\Omega @ V_{GS} = -4.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- SOP-8 package design

Product Description

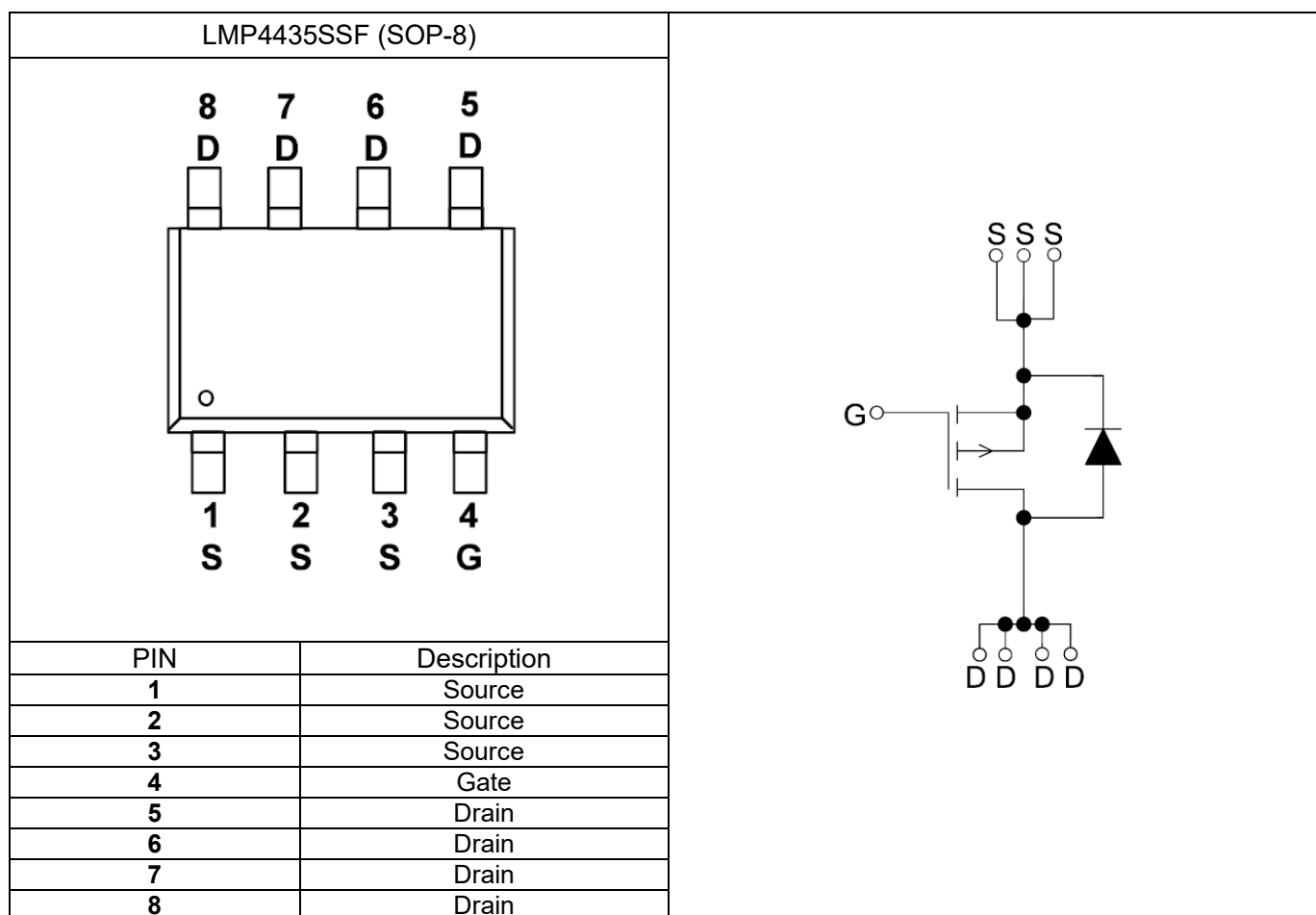
LMP4435SSF, P-Channel enhancement mode MOSFET, uses Advanced Trench Technology to provide excellent $R_{DS(ON)}$, low gate charge.

These devices are particularly suited for low voltage power management, such as smart phone and notebook computer, and low in-line power loss are needed in commercial industrial surface mount applications.

Applications

- LED Display
- CCFL Inverter
- Power Management in Notebook computer
- Load/Power Switching

Pin Configuration



Ordering Information

Ordering Information					
Part Number	P/N	PKG code	Pb Free code	Package	Quantity
LMP4435SSF	LMP4435S	S	F	SOP-8	4000

Marking Information

Marking Information		
Part Marking	Part Number	LFC code
4435S AAAAAA BBBBBB	AAAAAA	BBBBBB

Absolute Maximum Ratings

(T_C=25°C Unless otherwise noted)

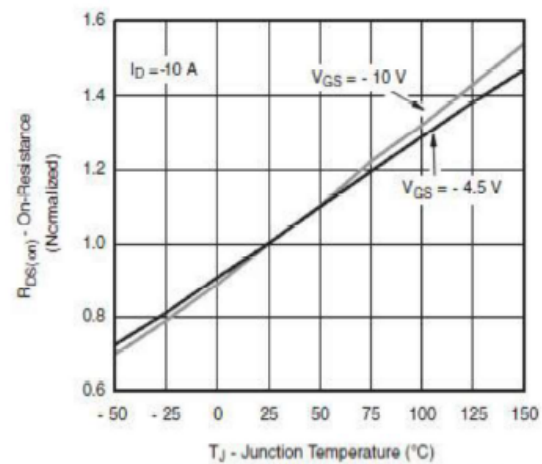
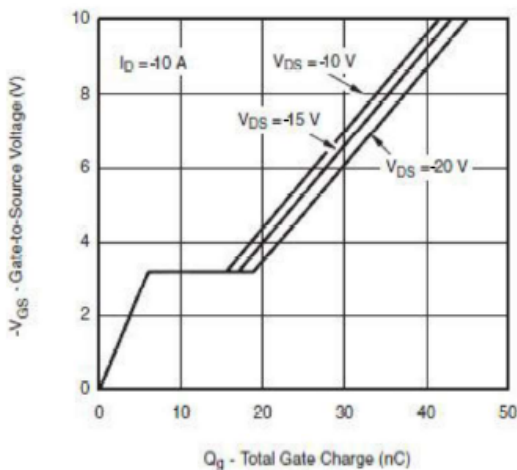
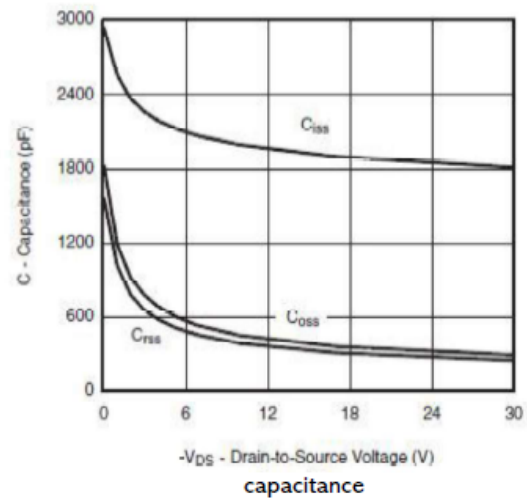
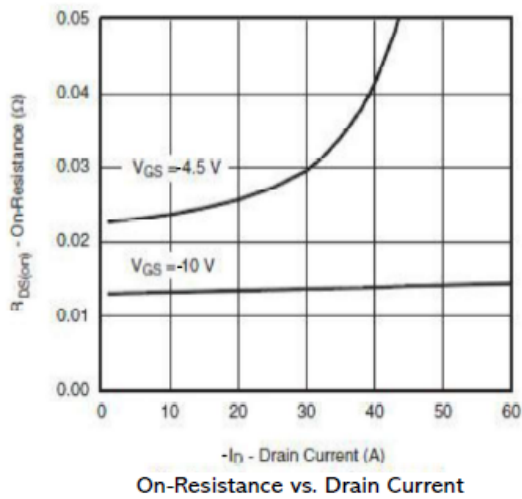
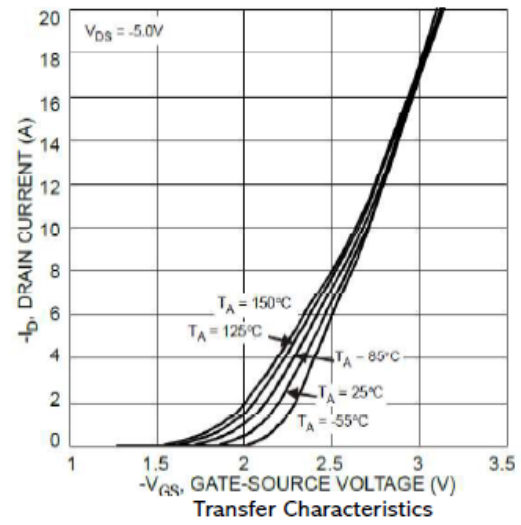
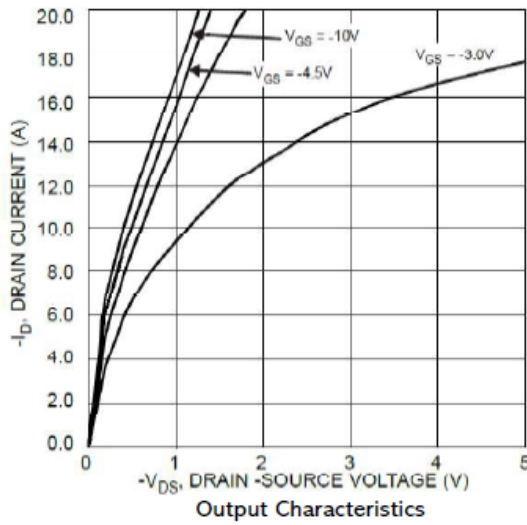
Symbol	Parameter	Typical	Unit
V _{DSS}	Drain-Source Voltage	-30	V
V _{GSS}	Gate Source Voltage	±20	V
I _D	Continuous Drain Current(T _J =150°C)	T _A =25°C	A
		T _A =70°C	
I _D _M	Pulsed Drain Current	-32	A
I _S	Continuous Source Current(Diode Conduction)	-2	A
P _D	Power Dissipation	T _A =25°C	W
		T _A =70°C	
T _J	Operating Junction Temperature	-55/150	°C
T _{STG}	Storage Temperature Range	-55/150	°C
R	Thermal Resistance-Junction to Ambient	62.5	°C/W
R _C	Thermal Resistance-Junction to Case	38	°C/W

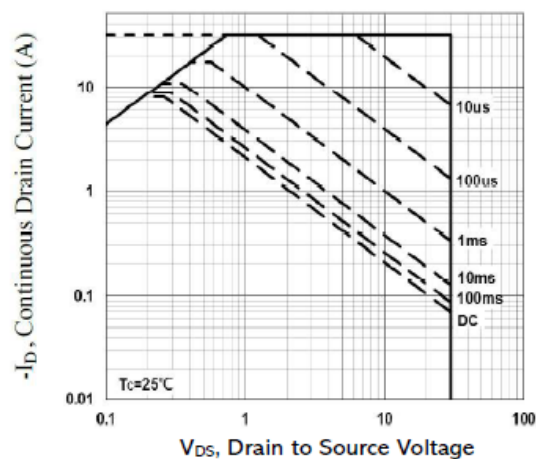
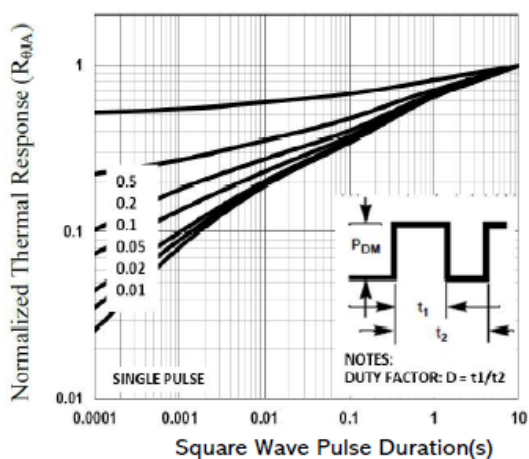
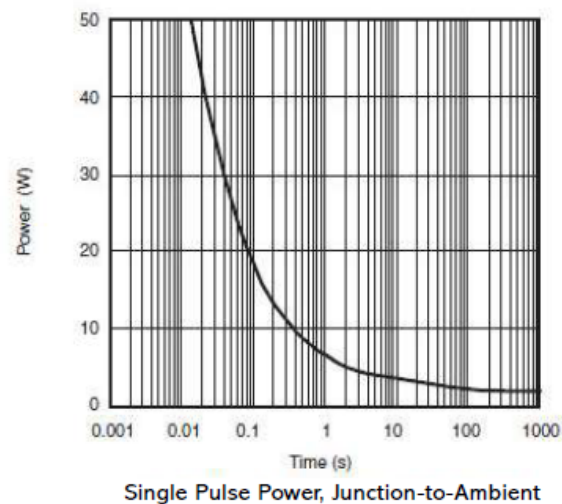
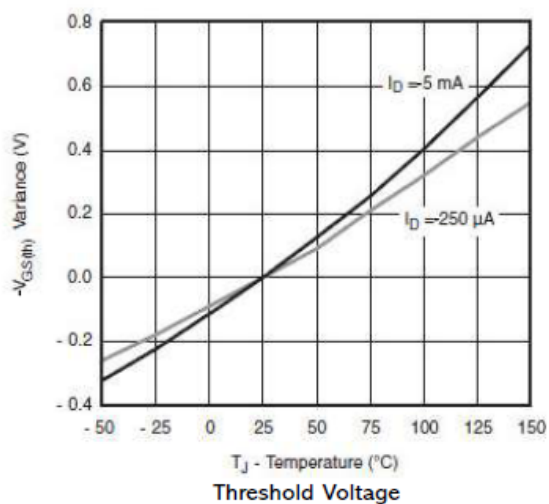
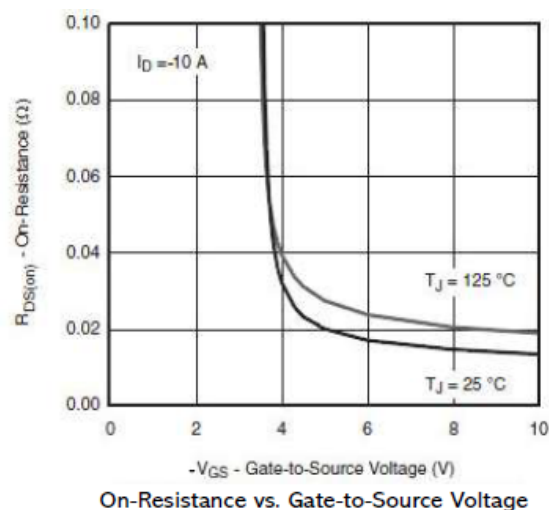
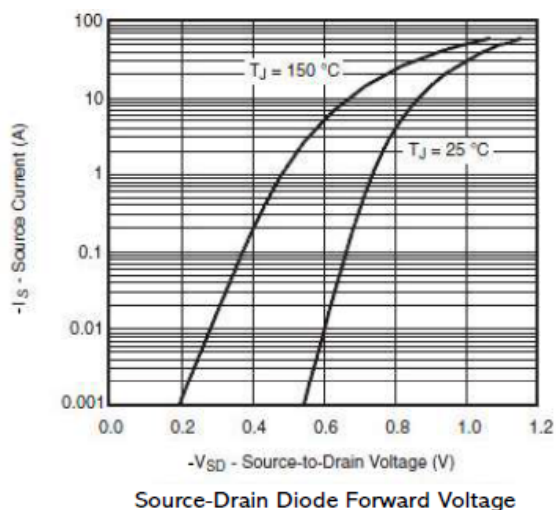
Electrical Characteristics

(T_C=25°C Unless otherwise noted)

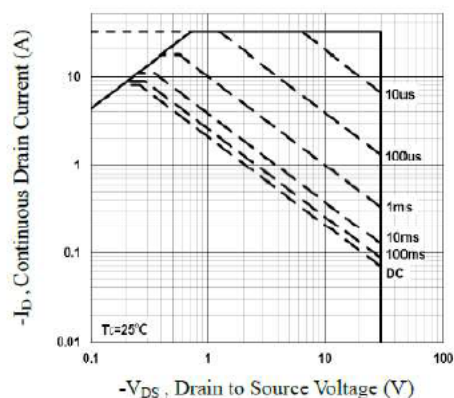
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250uA	-30			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250uA	-1.0		-2.0	
I _{GSS}	Gate Leakage Current	V _{DS} =0V, V _{GS} =±25V			±100	nA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-24V, V _{GS} =0V			-1	uA
		V _{DS} =-24V, V _{GS} =0V, T _J =85°C			-30	
I _{D(on)}	On-State Drain Current	V _{DS} -10V, V _{GS} =-10V	-30			A
		V _{DS} -5V, V _{GS} =-4.5V	-5			
R _{DS(on)}	Drain-Source On-Resistance	V _{GS} =-10V, I _D =-9A		10	18	mΩ
		V _{GS} =-4.5V, I _D =-7A		16	26	
g _{FS}	Forward Transconductance	V _{DS} =-10V, I _D =-9A		22		S
V _{SD}	Diode Forward Voltage	I _S =-2.3A, V _{GS} =0V		-0.7	-1.3	V
Dynamic						
Q _g	Total Gate Charge	V _{DS} =-15V, V _{GS} =-4.5V, I _D =-6A		2 0	30	nC
Q _{gs}	Gate-Source Charge			6		
Q _{gd}	Gate-Drain Charge			1 0		
C _{iss}	Input Capacitance	V _{DS} =-15V, V _{GS} =0V, f=1MHz		1600		pF
C _{oss}	Output Capacitance			350		
C _{rss}	Reverse Transfer Capacitance			300		
t _{d(on)}	Turn-On Time	V _{DD} =-15V, R _L =3Ω, I _D =-5A, V _{GEN} =-10V, R _G =1Ω		10	20	ns
t _r				12	24	
t _{d(off)}	Turn-Off Time			30	45	
t _f				10	20	

Typical Performance Characteristics

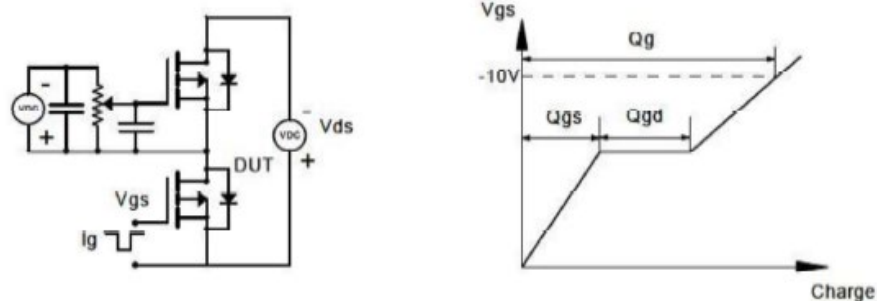


Typical Performance Characteristics(continue)


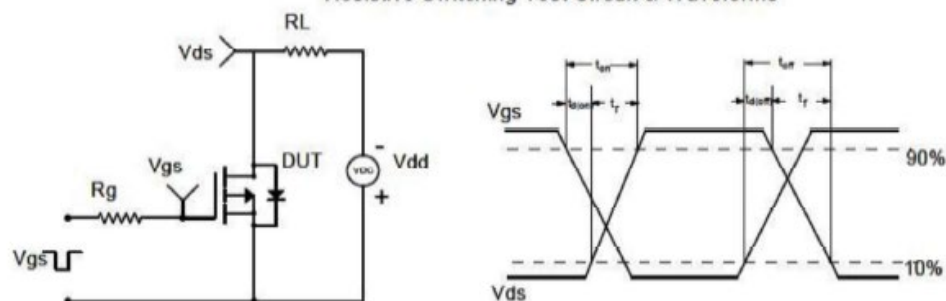
Typical Performance Characteristics(continue)



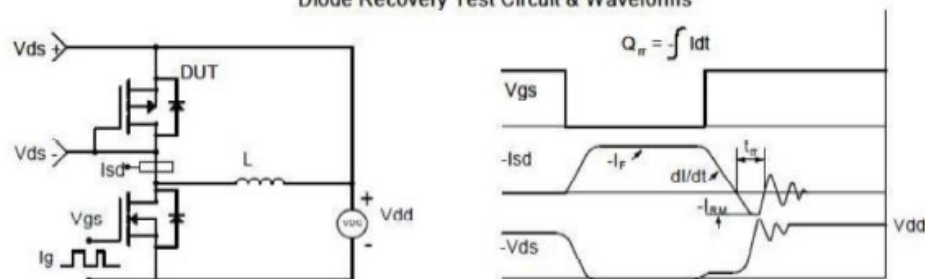
Gate Charge Test Circuit & Waveform

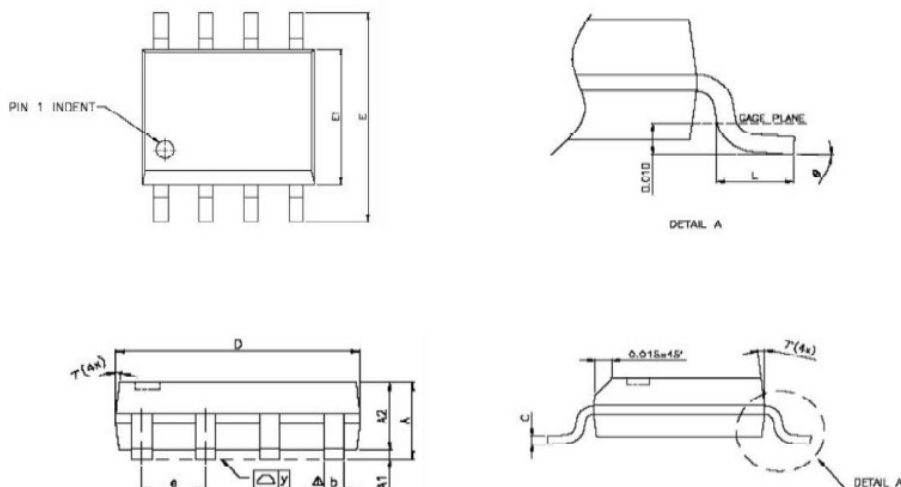


Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Dimension:
SOP-8


DIMENSION D AND E1 DO NOT INCLUDE MOLD FLASH, TIE BAR BURRS, GATE BURRS, AND INTERLEAD FLASH, NOT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.

Dimensions						
Symbol	Millimeters			Inches		
	Min	Nom	Max	Min	Nom	Max
A	1.47	1.60	1.73	0.058	0.063	0.068
A1	0.10	-	0.25	0.004	-	0.010
A2	-	1.45	-	-	0.057	-
b	0.33	0.41	0.51	0.013	0.016	0.020
C	0.19	0.20	0.25	0.0075	0.008	0.0098
D	4.80	4.85	4.95	0.189	0.191	0.195
E	5.80	6.00	6.20	0.228	0.236	0.244
E1	3.80	3.90	4.00	0.150	0.154	0.157
e	-	1.27	-	-	0.050	-
L	0.38	0.71	1.27	0.015	0.028	0.050
θ	0°	-	8°	0°	-	8°

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